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#### Be and C mixed material studies

## Parametric studies on carbon chemical erosion mitigation dynamics in Be seeded deuterium plasmas

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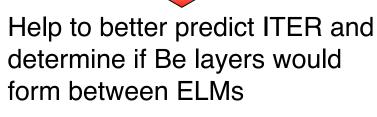


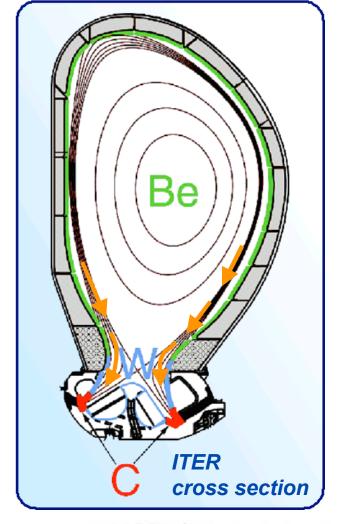
### In ITER strike point region, strong interaction between Be and C is anticipated

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- Previous results from PISCES-B; Carbon erosion is reduced by Be impurity in the plasma.
- Next questions:
  - How quickly is carbon erosion suppressed by Be layers formation?
  - What are the important parameters responsible for carbon erosion mitigation time (protecting Be layer formation time)?



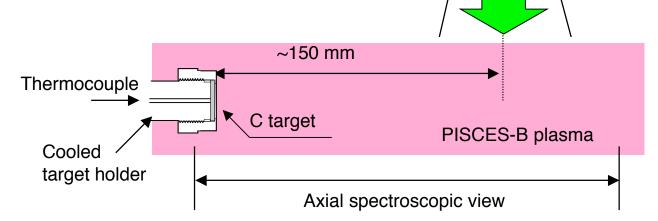




### PISCES-B allows to expose a sample to Be seeded plasma

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- The concentration of Be ion within the plasma column, measured with absolutely calibrated spectroscopic system, can be controlled by varying the temperature of the oven.
- Axial profile of CD band emission is monitored to characterize carbon chemical erosion.





Be

### Small amount of Be impurity in the plasma suppresses carbon chemical erosion

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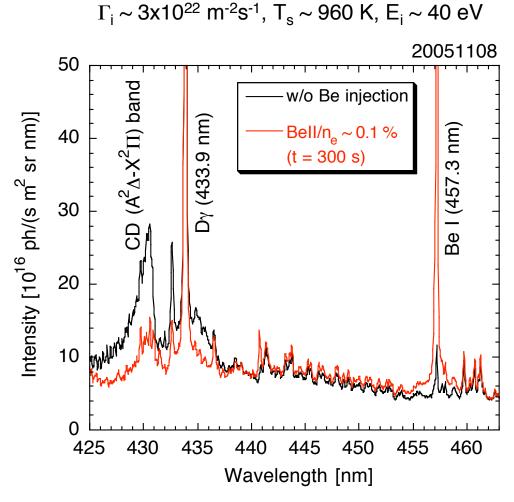
CD band intensity is decreased with Be injection.



Carbon chemical erosion is reduced.



Decay rate of CD band is used to measure Be surface coating time.

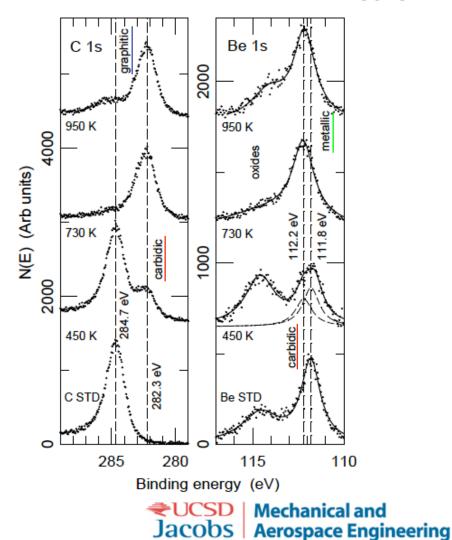


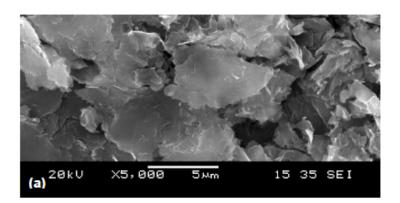


## XPS analysis shows formation of beryllium carbide (Be<sub>2</sub>C), responsible for carbon chemical erosion mitigation

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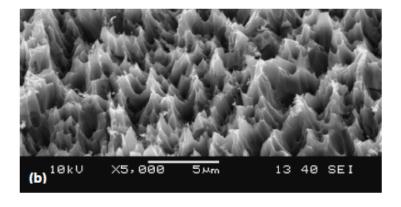
- XPS analysis of Be on C sample surface to examine chemical binding of elements
- After Be seeding D-plasma exposure,
  - A carbidic peak appears and a graphitic peak disappears in C 1s spectra.
  - Also in Be 1s spectra, a carbidic peak emerges.
  - Carbide forms more readily at higher surface temperature

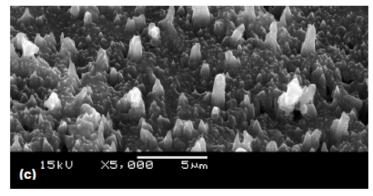




Unexposed ATJ graphite target Rough and porous surface (typical of machined graphite)

D plasma exposure with no Be D ion fluence  $\sim 2x10^{26}$  m<sup>-2</sup>, T<sub>s</sub>  $\sim 600$ K Cone like appearance (chemical erosion)





D/Be mixture plasma exposure

D ion fluence ~ 1.2x10 $^{26}$  m $^{-2}$ , BeII/n $_{\rm e}$  ~ 0.1 %, T $_{\rm s}$  ~ 600 K

Smoother surface (sub-micron level roughness), due to deposition of Be

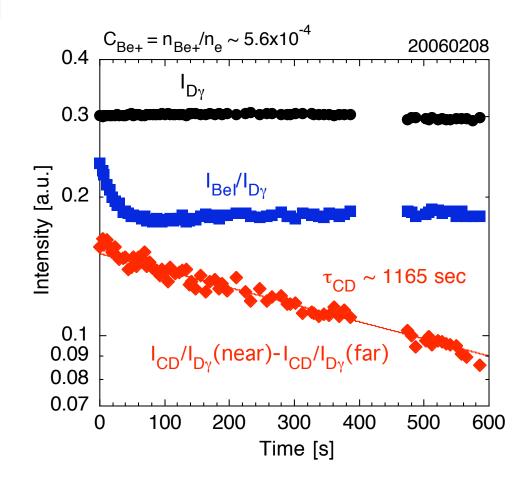
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- I<sub>Dγ</sub>: To monitor background plasma change
- $I_{Bel}/I_{D\gamma}$ :

  To monitor Be injection
- $I_{CD}/I_{D\gamma}$ (near)- $I_{CD}/I_{D\gamma}$ (far):

CD band intensity far from the target is subtracted from that near the target to eliminate changes in CD band originated from wall C.

n<sub>Be+</sub> from I<sub>BeII(467.3nm)</sub>





# Parametric studies on CD band decay time, in other words, protecting Be layer formation time

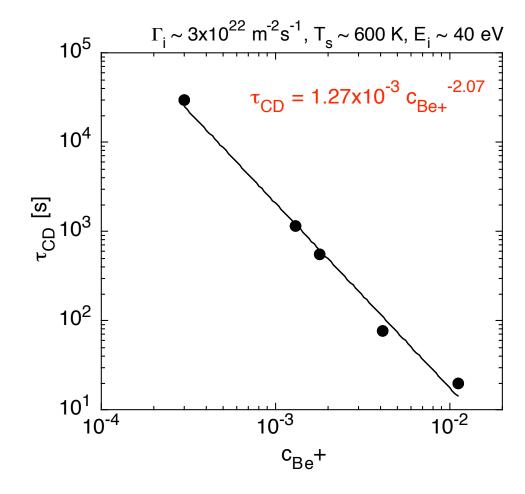
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#### Dependences on:

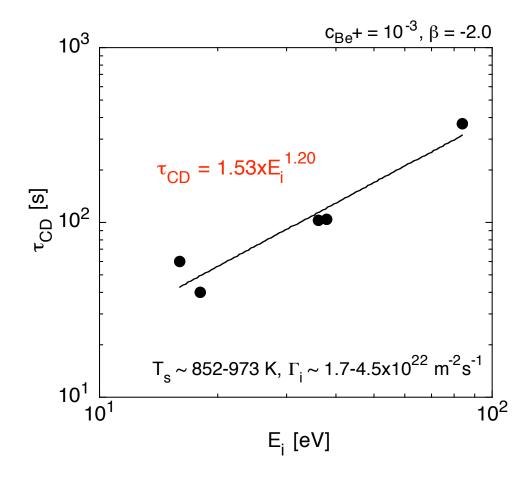
- Be ion concentration (c<sub>Be+</sub>)
- Incident ion energy (E<sub>i</sub>)
- Surface temperature (T<sub>s</sub>)
- Incident ion flux  $(\Gamma_i)$
- Scaling expression ( $c_{Be+}$ ,  $E_i$ ,  $T_s$ ,  $\Gamma_i$ )



- Scan  $c_{Be+}$  while keeping other parameters,  $E_i$ ,  $T_s$  and  $\Gamma_i$  constant as much as possible.
- Fit of power function,  $\tau_{CD} = \alpha \ c_{Be+}^{\ \beta}, \ gives$   $\alpha = 1.27 \times 10^{-3}, \ \beta = -2.07,$  showing relatively strong dependence.
- Scan each parameter, E<sub>i</sub>,
   T<sub>s</sub> and Γ<sub>i</sub>, while keeping
   others ~constant



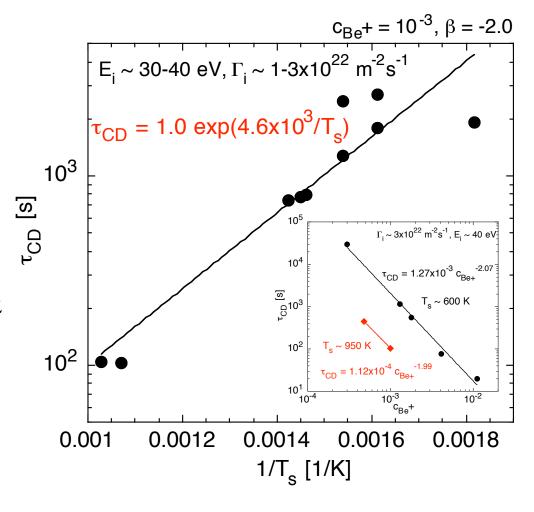
- Derive  $\tau_{CD}$  at  $c_{Be+} = 10^{-3}$  by assuming  $\beta = -2.0$  in power law  $\tau_{CD} = \alpha c_{Be+}^{\beta}$  to compensate  $c_{Be+}$  dependence.
- A power function fit reveals  $\tau_{CD}$  is nearly proportional to  $E_i$ .
- At higher incident energy, Be deposited on C target can be more readily sputtered before Be<sub>2</sub>C is formed, resulting in longer τ<sub>CD</sub>.







- At a higher surface temperature  $T_s$  of  $\sim$  950 K,  $\tau_{CD}$  is shorter than that at  $T_s \sim$  600 K by a factor of  $\sim$  20.
- Quicker formation of beryllium carbide (Be<sub>2</sub>C) at higher T<sub>s</sub>.
- The parameter  $\beta$  in  $\tau_{CD} = \alpha$   $c_{Be+}^{\beta}$  at  $T_s \sim 950$  K is nearly the same as that at  $T_s \sim 600$  K.
  - $\Rightarrow$  The same trend with respect to  $c_{Be+}$ .



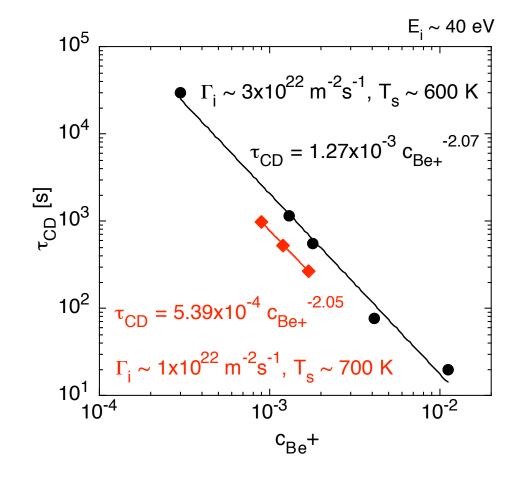




### $\tau_{CD}$ has possibly a very weak dependence on incident ion flux

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- At a lower incident ion flux of ~  $1x10^{22}$  m<sup>-2</sup>s<sup>-1</sup>,  $\tau_{CD}$  is found to be approximately 2.5 times smaller than that at  $\Gamma_{i}$  ~  $3x10^{22}$  m<sup>-2</sup>s<sup>-1</sup>.
- However, higher  $T_s$  can lead to shorter  $\tau_{CD}$ .
- Again, the parameter β is about -2.





### $\tau_{CD}^{exp}$ obey the scaling law well;

 $\tau_{CD}^{scale}$  [s] = 1.1e-7  $c_{Be+}^{-1.85}$   $E_i^{1.0}$   $\Gamma_i^{-0.5}$  exp(4.7e3/ $T_s$ )

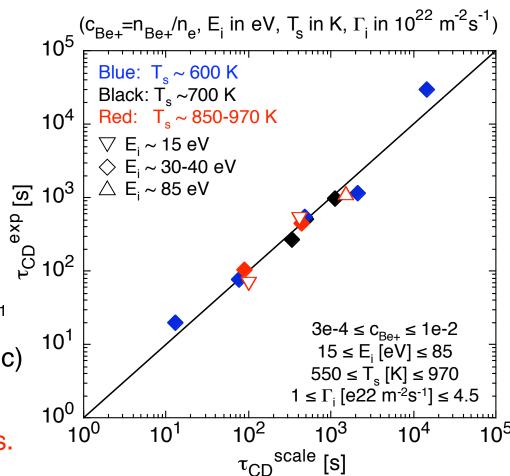
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- Weak negative power law dependence on  $\Gamma_i$ .
- At higher flux, redeposition fraction of Be is increased, leading to shorter  $\tau_{CD}$ .
- Extrapolation to ITER\*

$$\begin{cases} c_{Be+} = 0.05, \ E_i = 20 \ eV \\ T_s = 1200 \ K, \ \Gamma_i = 10^{23} \ m^{-2} s^{-1} \end{cases}$$

$$\Rightarrow$$
  $\tau_{CD} \sim 9$  msec (<< 1 sec)

 Protecting Be layers can be formed between ELMs.



\*G. Federici et al., JNM 266-269 (1999) 14.



- Small beryllium concentration in the plasma suppresses carbon chemical erosion.
- XPS analysis shows beryllium carbide (Be<sub>2</sub>C) layer is formed on a carbon sample after Be seeding deuterium plasma exposure with the surface temperature above 450 K.
- Parametric studies on carbon chemical erosion mitigation dynamics reveal the following dependences;

Strong Surface temperature exp(4.7e3/T<sub>s</sub>) (600 K - 970 K)

Weak

Be concentration  $c_{Be+}^{-1.9}$  (3x10<sup>-4</sup> - 1x10<sup>-2</sup>)

Incident ion energy E<sub>i</sub><sup>1.0</sup> (15 - 85 eV)

Incident ion flux  $\Gamma_i^{-0.5}$  (1-4.5x10<sup>22</sup> m<sup>-2</sup>s<sup>-1</sup>)

• More work is still needed at higher  $T_s$ , higher  $E_i$  and higher  $\Gamma_i$ .